



RADIO TEST REPORT

Test Report No. : 31HE0013-HO-01-B-R1

Applicant : Sony Corporation
Type of Equipment : Tablet Device
Model No. : SGPT211US/S
FCC ID : AK8SGPT211US
Test regulation : FCC Part 15 Subpart C: 2010
Test Result : Complied

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6. This report is a revised version of 31HE0013-HO-01-B. 31HE0013-HO-01-B is replaced with this report.

Date of test: February 16 to May 3, 2011

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13-EM-F0429

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SECTION 1: Customer information

Company Name : Sony Corporation
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Contact Person : Ryui Tatsumi

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Tablet Device
Model No. : SGPT211US/S
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : January 17, 2011
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: SGPT211US/S (referred to as the EUT in this report) is the Tablet Device.

Feature of EUT: This model is co-located with Wireless LAN(IEEE802.11b/g/n)/Bluetooth module and Wireless WAN module(GPRS/EDGE/HSPA/WCDMA). Each antenna is included in the equipment. This model can be co-operated Wireless WAN + Wireless LAN and Wireless WAN + Bluetooth. However, Wireless LAN and Bluetooth cannot be co-operated.

Radio Specification

Bluetooth

Equipment Type	Transceiver
Frequency of Operation	2402-2480MHz
Other Clock Frequency	26MHz, 38.4MHz, 32.768kHz
Type of Modulation	FHSS
Bandwidth & Channel spacing	1MHz & 1MHz
Antenna Type	Inverted-F
Antenna Gain	1.5dBi
Antenna Connector Type	N/A

WLAN (IEEE802.11b/g/n-20)

Equipment Type	Transceiver
Frequency of Operation	2412-2462MHz
Other Clock Frequency	26MHz, 38.4MHz, 32.768kHz
Type of Modulation	DSSS, OFDM
Bandwidth & Channel spacing	20MHz & 5MHz
Antenna Type	Inverted-F
Antenna Gain	1.5dBi
Antenna Connector Type	N/A

GSM

Equipment Type	Transceiver
Frequency of Operation	[Up Link] GSM850: 824 – 849MHz PCS: 1850 – 1910MHz [Down Link] GSM850: 869 – 894MHz PCS: 1930 – 1990MHz
Type of Modulation	GMSK , 8PSK
Bandwidth & Channel spacing	200kHz & 200kHz
Antenna Type	Inverted-F
Antenna Gain	2.5dBi
Antenna Connector Type	U.FL Compatible connector

W-CDMA

Equipment Type	Transceiver
Frequency of Operation	[Up Link] Band V: 824 – 849MHz Band II: 1850 – 1910MHz [Down Link] Band V: 869 – 894MHz Band II: 1930 – 1990MHz
Type of Modulation	QPSK
Bandwidth & Channel spacing	5MHz & 200kHz
Antenna Type	Inverted-F
Antenna Gain	2.5dBi
Antenna Connector Type	U.FL Compatible connector

GPS

Equipment Type	Receiver
Receiving Frequency	1575.42MHz
Type of Modulation	Spread Spectrum modulation
Bandwidth	2.046MHz
Antenna Type	Inverted-F
Antenna Connector Type	U.FL Compatible connector

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2010, final revised on December 6, 2010 and effective January 5, 2011

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.247 Operation within the bands 902-928MHz,
2400-2483.5MHz, and 5725-5850MHz

* The EUT complies with FCC Part 15 Subpart B: 2010, final revised on December 6, 2010 and effective January 5, 2011

3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC powerline Conducted Emission measurements IC: RSS-Gen 7.2.4	FCC: Section 15.207 IC: RSS-Gen 7.2.4	QP 20.0dB, 0.19970MHz, L AV 15.9dB, 0.20050MHz, N	Complied	-
6dB Bandwidth	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: RSS-Gen 4.6.2	FCC: Section 15.247(a)(2) IC: RSS-210 A8.2(a)	See data.	Complied	Conducted
Maximum Peak Output Power	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: RSS-Gen 4.8	FCC: Section 15.247(b)(3) IC: RSS-210 A8.4(4)		Complied	Conducted
Power Density	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: -	FCC: Section 15.247 (e) IC: RSS-210 A8.2(b)		Complied	Conducted
Spurious Emission Restricted Band Edges	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: RSS-Gen 4.9	FCC: Section15.247(d) IC: RSS-210 A8.5 RSS-Gen 7.2.3	5.0dB 75.567MHz, QP, Horizontal 11b Tx 2437MHz 11n Tx 2412MHz	Complied	Conducted/ Radiated

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

FCC 15.31 (e)

This EUT provides stable voltage(DC3.3/1.8V) constantly to RF Part regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	-	Conducted

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.1dB
No.2	3.3dB
No.3	3.7dB
No.4	3.2dB

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	3.5dB	5.1dB	5.2dB	4.8dB	5.1dB	4.4dB	4.3dB
No.2	4.0dB	5.1dB	5.2dB	4.8dB	5.0dB	4.3dB	4.2dB
No.3	4.2dB	4.7dB	5.2dB	4.8dB	5.0dB	4.5dB	4.2dB
No.4	4.0dB	5.0dB	5.1dB	4.8dB	5.0dB	5.1dB	4.2dB

*3m/1m/0.5m = Measurement distance

Power meter (+dB)	
Below 1GHz	Above 1GHz
1.0dB	1.0dB

Antenna terminal conducted emission and Power density (+dB)			Antenna terminal conducted emission (+dB)		Channel power (+dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.0dB	1.1dB	2.7dB	3.2dB	3.3dB	1.5dB

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Mode	Remarks*
IEEE 802.11b (11b)	5.5Mbps, PN9
IEEE 802.11g (11g)	24Mbps, PN9
IEEE 802.11n SISO 20MHz BW (11n-20)	MCS4, PN9
*The worst condition was determined based on the test result of Maximum Peak Output Power (Mid Channel)	
*Power of the EUT was set by the software as follows; Power setting: 11b 13.0dBm, 11g 11.5dBm, 11n-20 11.5dBm Software/version: tcommand/SDK3.1 Build-187 *This setting of software is the worst case. Any conditions under the normal use do not exceed the condition of setting. In addition, end users cannot change the settings of the output power of the product.	

*Details of Operating mode(s)

Test Item	Operating Mode	Tested frequency
Conducted Emission Spurious Emission	11b Tx 11g Tx 11n-20 Tx	2412MHz 2437MHz 2462MHz
Spurious Emission (Radiated)	11b Tx + GSM850 (GPRS, GMSK) *1) 11n-20 Tx + W-CDMA Band II (RMC12.2kbps) *1)	2437MHz + 848.8MHz(251ch) 2437MHz + 1907.6MHz(9538ch)
Spurious Emission (Band Edge)	11b Tx + GSM850 (GPRS, GMSK) *1) 11n-20 Tx + W-CDMA Band II (RMC12.2kbps) *1)	2412MHz + 848.8MHz(251ch) 2462MHz + 1907.6MHz(9538ch)
6dB Bandwidth Maximum Peak Output Power Power Density 99% Occupied Bandwidth	11b Tx 11g Tx 11n-20 Tx	2412MHz 2437MHz 2462MHz

*1) Representative Wireless WAN mode that is possible of simultaneous communication with WLAN

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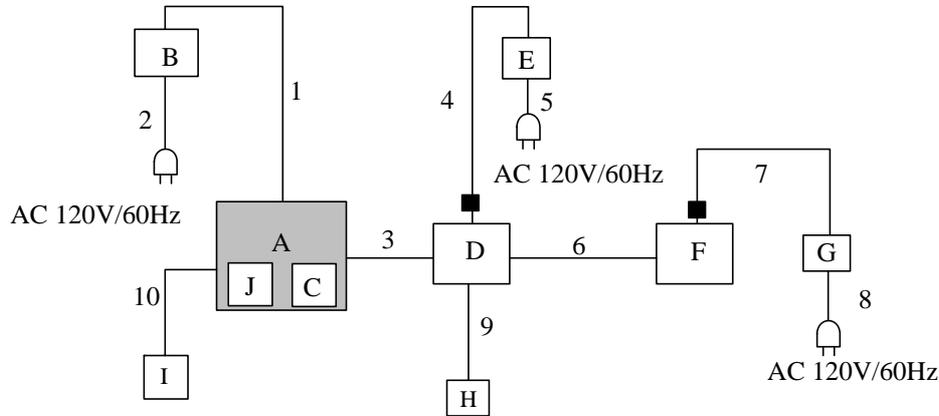
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4.2 Configuration and peripherals



■ : Standard Ferrite Core

* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Tablet Device	SGPT211US/S	DVT102006000444 *1) DVT102006000445 *2) DVT102004000011 *3)	SONY	EUT
B	AC Adapter	SGPAC5V2	148907411 11026000217	SONY	-
C	Micro SD Card	SR-2C1	F 1170000 052	SONY	-
D	Laptop PC	2373G07	L303T2G	IBM	-
E	AC Adapter	92P1020	11592P1020Z1Z9RM67H1Y C	IBM	-
F	Printer	C6414A	CN0B11C1H2	Hewlett Packard	-
G	AC Adapter	C6409-60014	0049R0D	Hewlett Packard	-
H	USB Mouse	X05-89304	52779-576-1794482-0	Microsoft	-
I	Headset	-	-	SONY	-
J	Rechargeable Lithium Ion Battery Pack	SGPBP01	175699711 0000661 1124	SONY	-

*1) Used for Radiated emission test performed after April 15, 2011

*2) Used for Conducted emission test and Radiated emission test performed before April 15, 2011

*3) Used for Antenna Terminal Conducted test

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	DC Cable	1.5	Unshielded	Unshielded	-
2	AC Cable	1.5	Unshielded	Unshielded	-
3	USBCable	1.5	Shielded	Shielded	-
4	DC Cable	1.8	Unshielded	Unshielded	-
5	AC Cable	0.9	Unshielded	Unshielded	-
6	Pararell Cable	2.0	Shielded	Shielded	-
7	DC Cable	2.0	Unshielded	Unshielded	-
8	AC Cable	1.8	Unshielded	Unshielded	-
9	USB Cable	0.8	Shielded	Shielded	-
10	Headset Cable	1.2	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber. The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Detector	: QP and AV
Measurement range	: 0.15-30MHz
Test data	: APPENDIX
Test result	: Pass

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SECTION 6: Radiated Spurious Emission

Test Procedure

It was measured based on "2. Radiated emission test" of "Guidance on Measurement of Digital Transmission Systems Operating under Section 15.247".

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Biconical	Logperiodic	Horn

In any 100kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 5 of RSS-Gen 7.2.5(IC) and outside the restricted band of FCC15.205 / Table 3 of RSS-Gen 7.2.2 (IC).

Frequency	Below 1GHz	Above 1GHz		20dBc
Instrument used	Test Receiver	Spectrum Analyzer		Spectrum Analyzer
Detector	QP	PK	AV	PK
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz VBW: 3MHz	RBW: 1MHz VBW: 10Hz	RBW: 100kHz VBW: 300kHz (S/A)
Test Distance	3m	3m (below 10GHz), 1m*1) (above 10GHz),		3m (below 10GHz), 1m*1) (above 10GHz),

*1) Distance Factor: $20 \times \log(3.0\text{m}/1.0\text{m}) = 9.5\text{dB}$

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT and each angle of 0, 90, and 180 degree of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 30M-25GHz
Test data : APPENDIX
Test result : Pass

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SECTION 7: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
6dB Bandwidth	20MHz	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak	-	Power Meter (Sensor: 50MHz BW)
Peak Power Density	18MHz	30kHz	100kHz	600sec	Peak	Max Hold	Spectrum Analyzer *1) *2)
Conducted Spurious Emission *3)	9kHz to 150kHz	200Hz	620Hz	Auto	Peak	Max Hold	Spectrum Analyzer
	150kHz to 30MHz	10kHz	30kHz				
	30MHz to 25GHz (Less or equal to 5GHz)	100kHz	300kHz				

*1) PSD Option 1 of "Guidance on Measurement of Digital Transmission Systems Operating under Section 15.247".

*2) The test was not performed at RBW:3kHz however the measurement is to be performed with RBW:3kHz in the regulation, because the measurement value with RBW:3kHz is less than the value of RBW:30kHz and the test data met the limit with RBW:30kHz.

*3) In the frequency range below 30MHz, RBW was narrowed to separate the noise contents. Then, wide-band noise near the limit was checked separately, however the noise was not detected as shown in the chart. (9kHz-150kHz:RBW=200Hz, 150kHz-30MHz:RBW=10kHz)

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : **APPENDIX**

Test result : **Pass**